

# Reliability Of High Mobility SiGe Channel MOSFETs For Future CMOS Applications (Springer Series In Advanced Microelectronics) By Jacopo Franco;Ben Kaczer;Guido Groeseneken

**By Jacopo Franco;Ben Kaczer;Guido Groeseneken**

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which is based on silicon germanium [20] AlGaAs/InGaAs pseudomorphic high electron mobility High-reliability GaAs-AlGaAs HBTs by MBE <http://www.nepp.nasa.gov/DocUploads/FA968B63-F711-46F4-95CE441207843BC1/NEPP-TRO-GaAs%20RF.doc>

SiGe channel MOSFETs for future CMOS applications. [Jacopo Springer series in advanced microelectronics, Jacopo Franco, Ben Kaczer, Guido Groeseneken. <http://www.worldcat.org/title/reliability-of-high-mobility-sige-channel-mosfets-for-future-cmos-applications/oclc/863151654>

the introduction of high mobility silicon germanium SiGe pFETs appear to be able to reach the current ITRS reliability targets. Band structure of SiGe  
<http://semiengineering.com/reliability-after-planar-silicon/>

The potential applications of strained SiGe alloys to high to their high carrier mobility, reliability also suggests that the high  
<http://iopscience.iop.org/0268-1242/18/1/305/fulltext/>

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Ben Kaczer is the author of Reliability of High Mobility SiGe Channel Mosfets for Future CMOS Applications (0.0 avg rating, 0 ratings, 0 reviews, publish  
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Abstract. With a significantly reduced Negative Bias Temperature Instability (NBTI), SiGe channel pMOSFETs promise to virtually eliminate this reliability issue for  
<http://www.sciencedirect.com/science/article/pii/S0167931713002074>

Enrico Zanoni(5) Guido Groeseneken(5) Impact of Off State Stress on advanced high-K metal gate NMOSFETs. (sSOI substrate, SiGe channel) planar FDSOI MOSFETs.  
[http://dblp.l3s.de/?q=ESSDERC&search\\_opt=venuesOnlyExact&newQuery=yes&resTableName=query\\_result3j2G5b&resultsPerPage=100](http://dblp.l3s.de/?q=ESSDERC&search_opt=venuesOnlyExact&newQuery=yes&resTableName=query_result3j2G5b&resultsPerPage=100)

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we have fabricated high mobility SiGe channel pMOSFETs after optimizing epitaxial Reliability of Strained SiGe Channel p-Channel Metal?Oxide  
<http://iopscience.iop.org/1347-4065/48/4S/04C055>

and U. K. Mishra, Proton irradiation effects on GaN-based high electron mobility the reliability of high-K Available High-Speed SiGe  
<http://www.isde.vanderbilt.edu/rer/publications/2004-journal-articles/>

We evaluated the thermal reliability of thin SiGe epilayers High Ge-content strained SiGe-on-Si is a useful channel material in high-mobility SiGe  
<http://www.sciencedirect.com/science/article/pii/S0169433211020174>

During the last decade many new concepts have been proposed for improving the performance of power MOSFETs. The results of this research are dispersed in the  
<http://www.ciao.de/sr/q-mosfet,tc-750808>

Future Students; Graduate Admissions CMOS Circuits for Piezoelectric Energy Harvesters : Efficient Power Extraction, Dordrecht : Springer, 2014 Online Access:  
<http://catalog.utt Tyler.edu/cgi-bin/koha/opac-search.pl?q=se:Springer%20series%20in%20advanced%20microelectronics>.

SiGe Channel Technology: Superior Reliability improved NBTI reliability for this family of high-mobility (Si and SiGe) high-kmetal gate CMOS technology with  
[http://www.iue.tuwien.ac.at/pdf/ib\\_2012/JB2012\\_Grasser\\_5.pdf](http://www.iue.tuwien.ac.at/pdf/ib_2012/JB2012_Grasser_5.pdf)

and diborane sources for the preparation of the B-doped Si This high mobility of the CVD SiGe Im by CVD and annealed at high temperature, the reliability of  
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